Issue CI	Issue Classification	Application/Control No. 10758317	Applicant(s)/Pa CHANG ET AL.	Applicant(s)/Patent under Reexamination CHANG ET AL.
		Examiner Deo, Duy-Vu N	Art Unit 1765	
	ORIGINAL	IAL	INTERNATIONAL	INTERNATIONAL CLASSIFICATION
CLASS	SS	SUBCLASS	CLAIMED	NON-CLAIMED
438		585	H 0 1 L 21 /4763 H 0 1 L 21 /3205	
	CROSS REFERENCE(S)	RENCE(S)		
CLASS	SUBCLASS (ON	SUBCLASS (ONE SUBCLASS PER BLOCK)		
438	587 591	791		
NONE (Assistant Examiner)	(Date)			Total Claims Allowed:
(Legal Instruments Example)	7 1/06 (Date)	Duy-Vu Deo (Primary Examiner)	9/5/06 (Date)	O.G. O.G. Print Claim(s) Print Figure

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